Ken BURCH
Assistant Professor
Department of Physics
University of Toronto
60 St. George Street Toronto
Ontario, Canada
M5S 1A7

Tuning Materials with Mechanical Exfoliation

Materials with Nanometer thickness are an appealing platform for devices as well as exploring the roles of dimensionality, disorder, and free carrier density in complex materials. To this end we have produced exfoliated crystals of Bi2Sr2CaCu2O8 and Bi2Se3 on a variety of substrates. I will discuss unique advantages of this technique as well as some of the challenges it posses. Interestingly we have observed subtle differences in the Raman spectra between the exfoliated and bulk crystals enabling noninvasive determination of thickness (Bi2Se3) and Doping level (Bi-2212).